

# FINAL PRODUCT/PROCESS CHANGE NOTIFICATION

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#### 07 Jan 2010

SUBJECT: ON Semiconductor Final Product/Process Change Notification #16384

<u>TITLE:</u> Qualification of NCP347, NCP348, NCP349 for Fabrication at ON Semiconductor Gresham Wafer Fab

PROPOSED FIRST SHIP DATE: 07 Apr 2010 or earlier with customer approval

AFFECTED CHANGE CATEGORY(S): ON Semi Fab Site

AFFECTED PRODUCT DIVISION(S): Computing and Consumer Products Group

#### FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Todd Manes<todd.manes@onsemi.com>

**SAMPLES:** Contact your local ON Semiconductor Sales Office

### **ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or Todd Manes<a href="mailto:docarea">todd.manes@onsemi.com</a>>

#### **NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

#### **DESCRIPTION AND PURPOSE:**

ON Semiconductor is pleased to announce that the NCP347, NCP348, and NCP349 product families are now qualified for production at ON Semiconductor's Gresham wafer fab (located in Gresham, Oregon).

Upon expiration or approval of the Final PCN, devices may be supplied from the Gresham wafer fab.

The Gresham wafer fab is compliant to ISO9001:2000, ISO/TS16949:2002, and ISO14001:2004. The devices have previously been manufactured at ON Semiconductor's Piestany, Slovakia wafer fab on the 0.8um PS5LV process. Devices are now qualified to run at Gresham on the 0.25um BCD process. Device performance is the same for the Gresham-sourced material as for the Piestany-sourced material. All devices continue to be assembled and tested in existing, qualified locations. No changes to packaging occur as a result of this wafer fab qualification.

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## **RELIABILITY DATA SUMMARY:**

Products sourced from the Gresham wafer fab continue to meet ON Semiconductor's standards and requirements. Reliability test results for Gresham qualification material are summarized below.

### **Reliability Test Results:**

Test HTOL	Conditions NCP347MTAHTBG, Tj=+150C, 336 hours	Results Pass
ESD:	NCP347MTAITBG, 2000V HBM NCP347MTAITBG, 200V MM	Pass Pass
LU:	NCP347MTAITBG, Class II +85C (100mA)	Pass

## **ELECTRICAL CHARACTERISTIC SUMMARY:**

There is no significant difference in electrical parametric performance for the Gresham-sourced material. Characterization data is available upon request.

## **CHANGED PART IDENTIFICATION:**

Products listed in this PCN with Finished Good date codes representing WW 14, 2010 or later will be assembled with die sourced from the Gresham wafer fab, unless earlier customer approval is obtained. If early customer approval is obtained, devices with date codes of WW 03, 2010 or later will be assembled with die from the Gresham wafer fab.

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# **AFFECTED DEVICE LIST**

NCP347MTAETBG

NCP347MTAITBG

NCP347MTAFTBG

NCP347MTAHTBG

NCP348AEMTTBG

NCP348AEMUTBG

NCP348MTTBG

NCP349MNAETBG

NCP349MNBGTBG

NCP349MNBKTBG

NCP349MNTBG

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